



Call for Papers



Honorary Chair
Marco Parvis

General Chairs
Voicu Groza
Rafik Goubran

Technical Program Co-Chairs
Sergio Rapuano
Hilmi Dajani

Publications Chairs
Miodrag Bolic
Domenico Grimaldi

Steering Committee
Martin Bouchard
Pasquale Daponte
Alessandro Ferrero
Radu Leca
Emil M. Petriu
Sreeraman Rajan

Conference Management
Chris Dyer

Local Arrangements Chairs
Raed Abdullah
Wahab Almuhtadi
Branislav Djokic



Medical instrumentation and measurement form the first link in the chain connecting engineering to medicine. At this stage, flaws may lead to a myriad of repercussions at all levels, starting with the safety and efficacy of care. The importance of measurement in medical applications is growing continuously as increasingly sophisticated techniques become available for general, unsupervised use.

The goal of this 5th edition of the MeMeA workshop is to present novel solutions to instrumentation and measurement problems encountered in modern health care. Main topics include:

- Sensors for medical systems;
- Sensor fusion and calibration;
- Embedded systems;
- Biosignal processing;
- Imaging and communication;
- Standards for medical applications.

Authors are invited to submit extended abstracts (3 pages) or draft papers reporting original research of theoretical or applied nature. The extended abstract should explain the significance of the contribution and list the key references. It must be prepared in English, according to the preparation guidelines available at the MeMeA 2010 website (<http://memea.ieee-ims.org>).

Important Dates:

February 14, 2010 Deadline for submission of extended abstracts.

March 2, 2010 Notification to authors of accept/reject decisions.

April 1, 2010 Deadline for submission of camera-ready, full-length papers.

Extended abstracts will be reviewed by the Technical Program Committee. Authors of accepted full-length papers, must register for the workshop and attend to present their papers. Authors of papers presented at the workshop will be allowed to submit expanded versions of their papers to the Special Issue of the IEEE Transactions on Instrumentation & Measurement on MeMeA 2010.